

Notice of References Cited

Application/Control No.

10/564,503

Applicant(s)/Patent Under
Reexamination
KABU ET AL.

Examiner

DAVID WEISZ

Art Unit

1797

Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0116746	06-2004	Ono et al.	564/267
*	B	US-6,057,482	05-2000	Okada et al.	568/705
	C	US-			
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	I	US-			
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	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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